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(12) **United States Design Patent**  
**Terada et al.**

(10) **Patent No.:** **US D447,967 S**

(45) **Date of Patent:** **\*\* Sep. 18, 2001**

(54) **MEASURING APPARATUS FOR  
MEASURING A PARTICLE SIZE  
DISTRIBUTION**

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Takarada**, Miki; **Kenichi Inami**, Kobe,  
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(57) **CLAIM**

The ornamental design for a measuring apparatus for mea-  
suring a particle size distribution, as shown and described.

(73) Assignee: **Sysmex Corporation**, Kobe (JP)

(\*\*) Term: **14 Years**

**DESCRIPTION**

(21) Appl. No.: **29/132,403**

FIG. 1 is a front view of a measuring apparatus for mea-  
suring a particle size distribution showing our new design;

(22) Filed: **Nov. 8, 2000**

FIG. 2 is a rear view thereof;

(51) **LOC (7) Cl.** ..... **10-04**

FIG. 3 is a left side view thereof;

(52) **U.S. Cl.** ..... **D10/75; D10/46**

FIG. 4 is a right side view thereof;

(58) **Field of Search** ..... **D10/46, 75; 250/575;  
356/336-338**

FIG. 5 is a top plan view thereof; and,

FIG. 6 is a bottom plan view thereof.

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

6,191,853 \* 2/2001 Yamaguchi et al. .... 356/336

\* cited by examiner

**1 Claim, 6 Drawing Sheets**

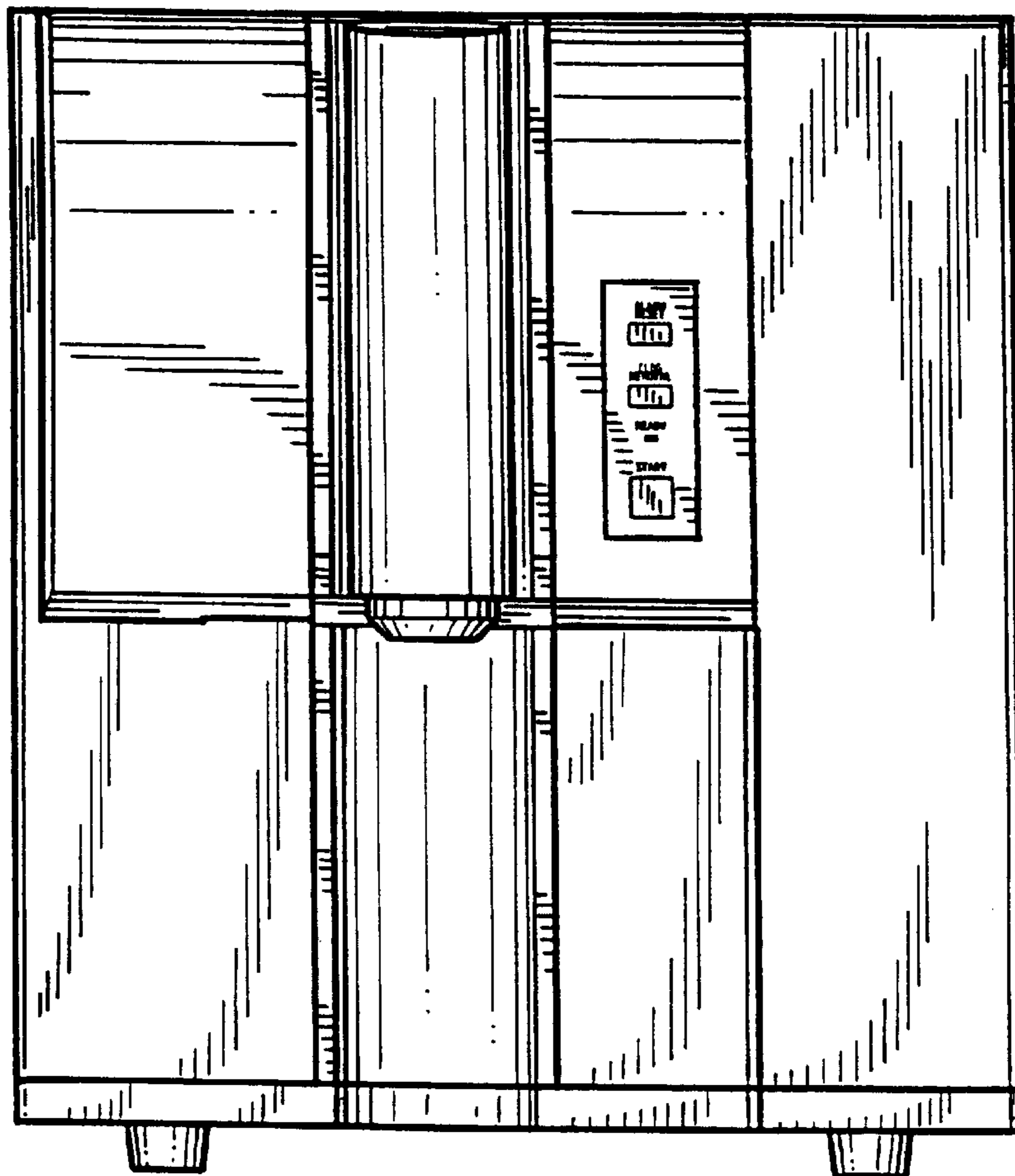


FIG. 1

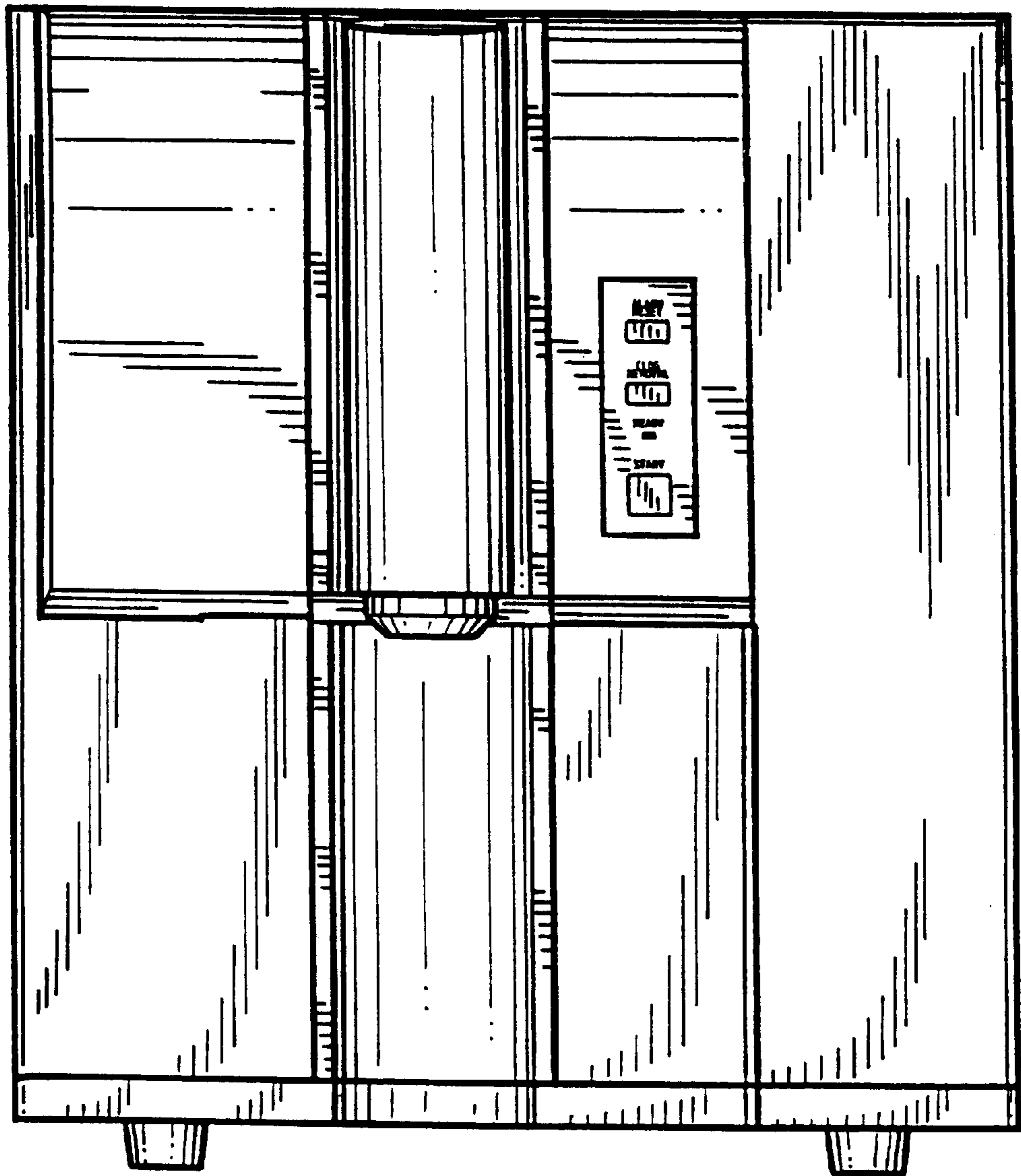


FIG. 2

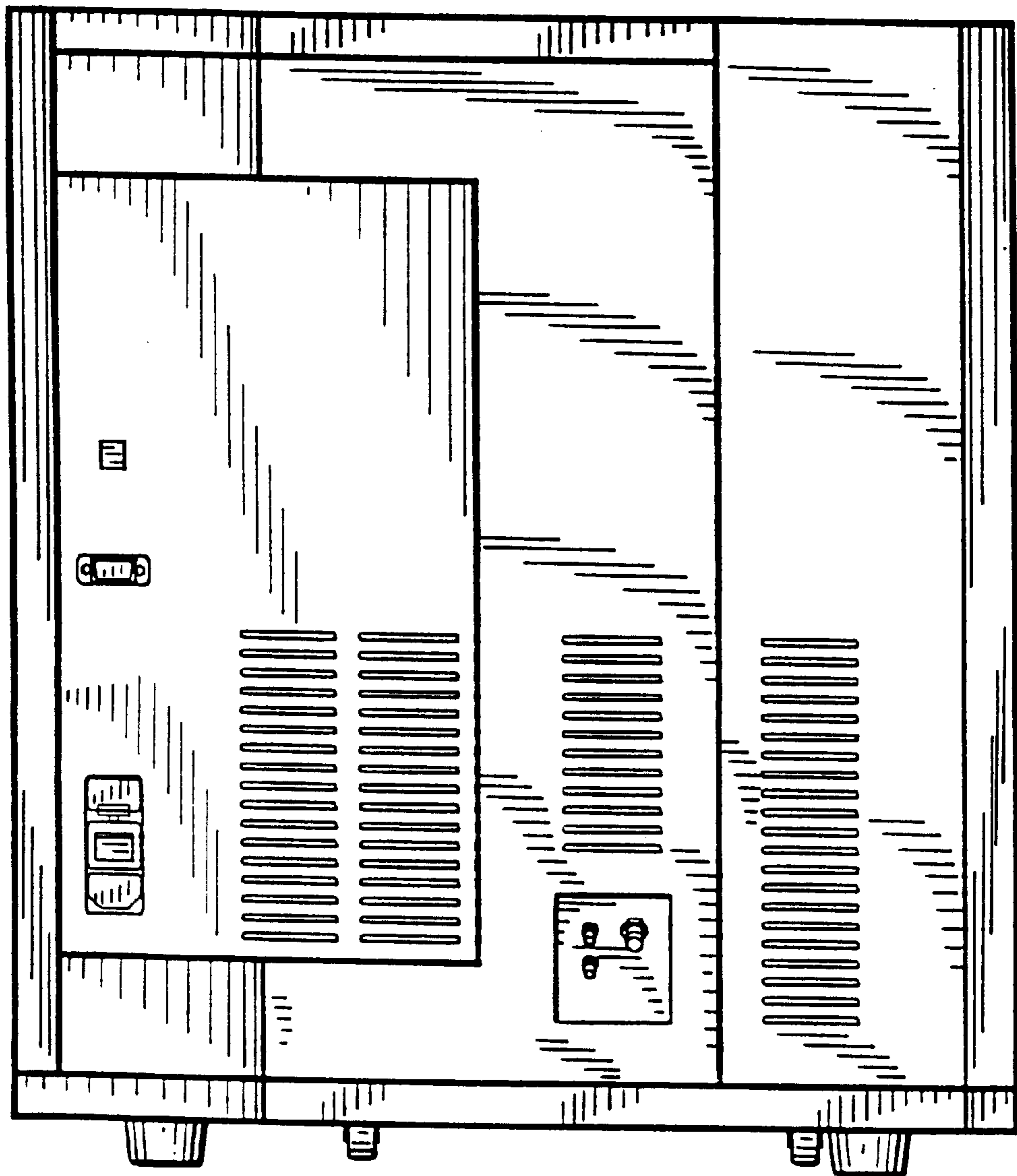


FIG. 3

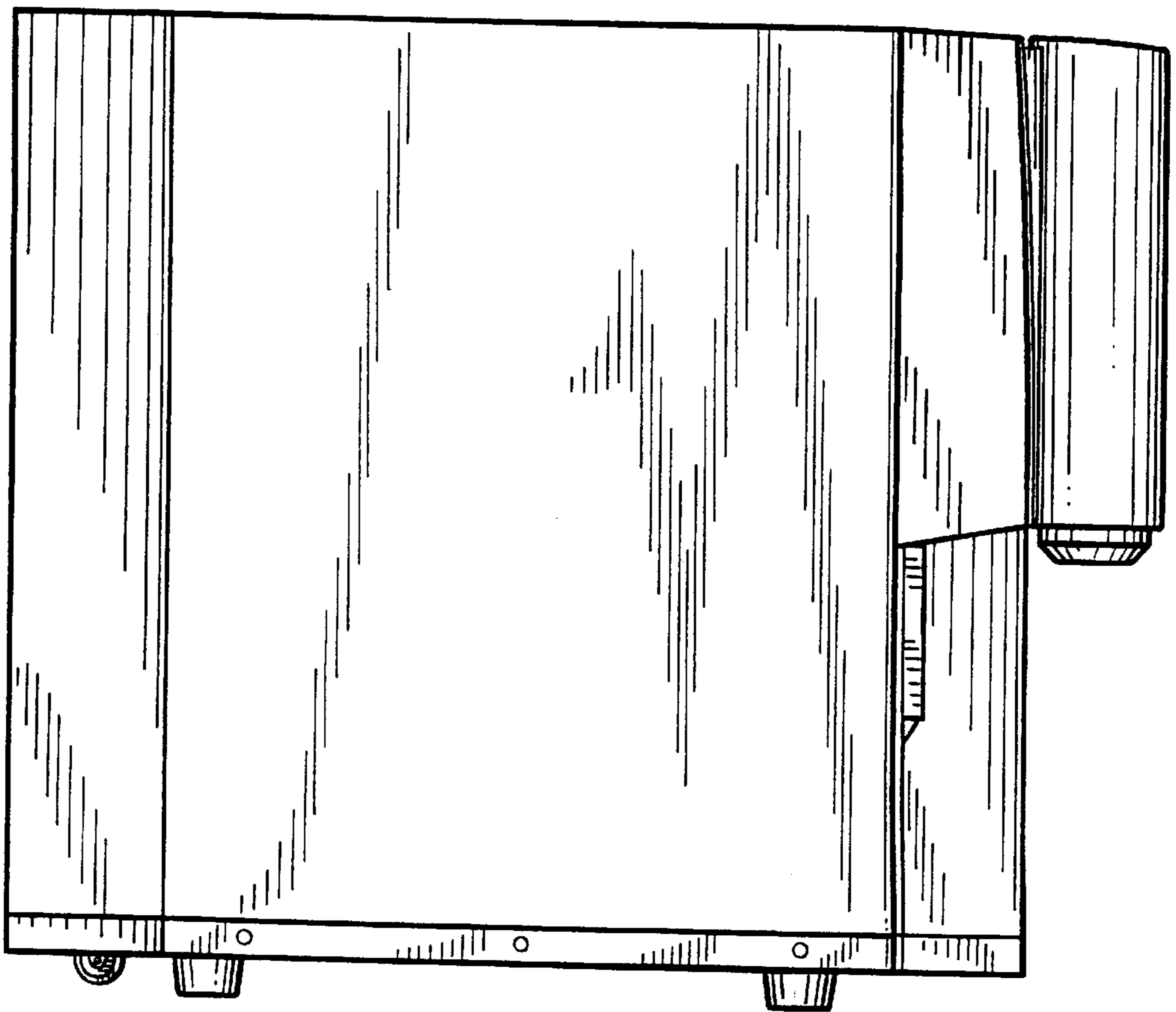


FIG. 4

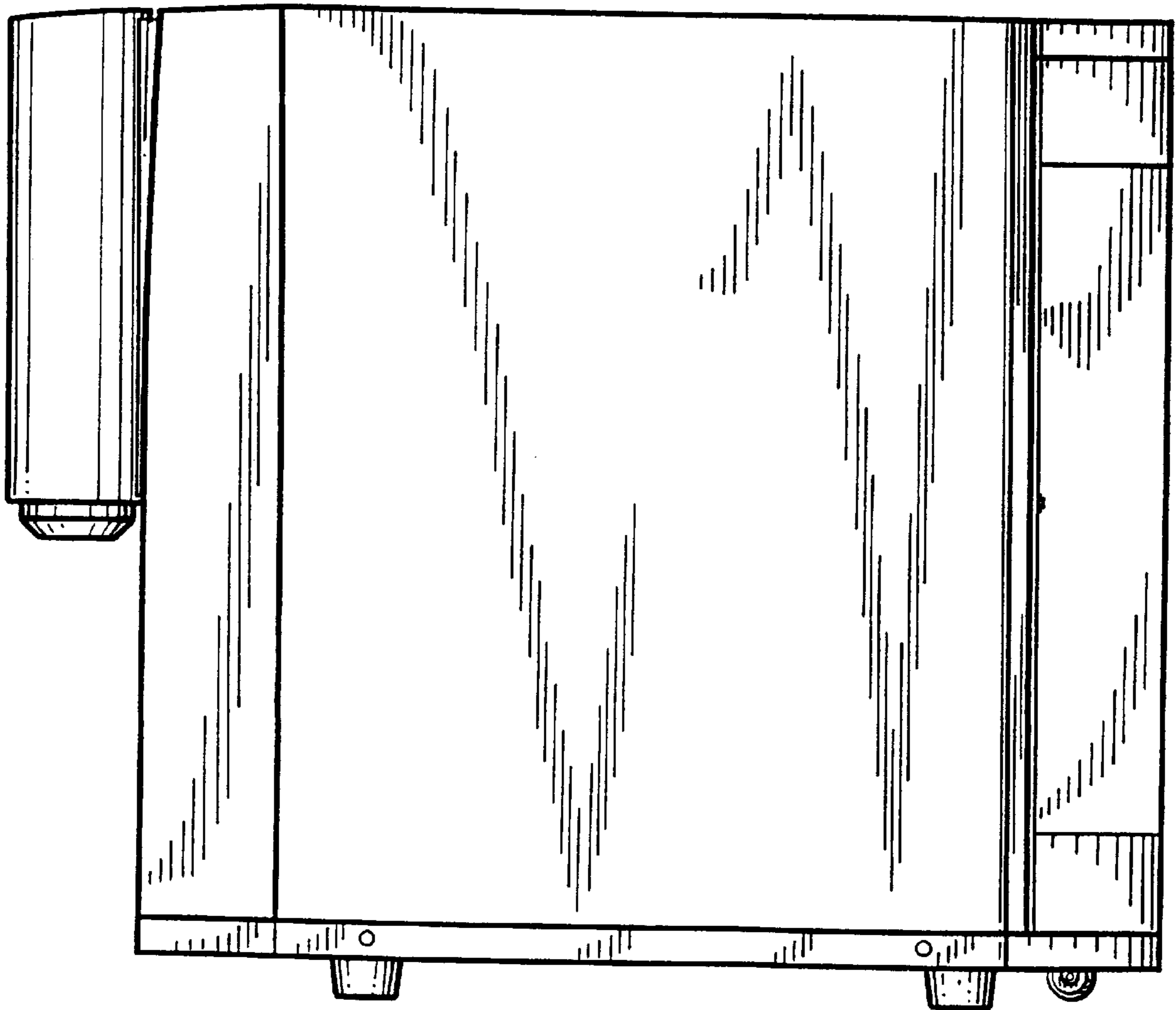


FIG. 5

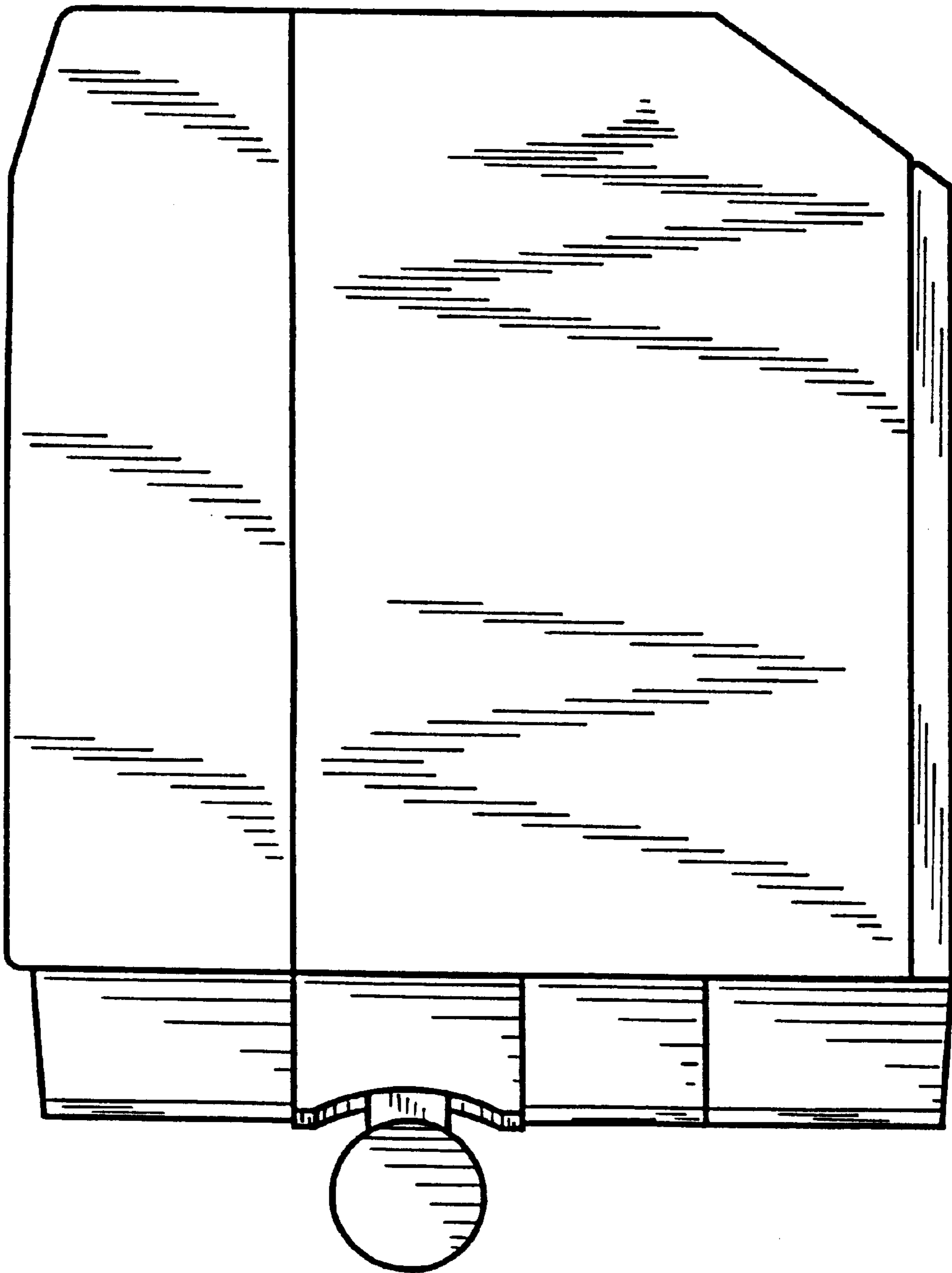


FIG. 6

